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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
09/955,076	09/19/2001	Eiji Sakagami	214019US2	9771
22×50 7.	590 07/18/2003			
OBLON, SPIVAK, MCCLELLAND, MAIER & NEUSTADT, P.C. 1940 DUKE STREET ALEXANDRIA, VA 22314			EXAMINER	
			WEISS, HOWARD	
			ART UNIT	PAPER NUMBER
			2814	

DATE MAILED: 07/18/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)				
Office Action Summary		09/955,076	SAKAGAMI, EIJI				
		Examiner	Art Unit				
		Howard Weiss	2814				
Period fo	The MAILING DATE of this communication ap or Reply	pears on the cover sheet w	vith the correspondence address				
A SHOTHE I - Exter after - If the - If NO - Failu - Any r	ORTENED STATUTORY PERIOD FOR REPL MAILING DATE OF THIS COMMUNICATION. nsions of time may be available under the provisions of 37 CFR 1. SIX (6) MONTHS from the mailing date of this communication. period for reply specified above is less than thirty (30) days, a replayer of the period for reply is specified above, the maximum statutory period reto reply within the set or extended period for reply will, by statutely received by the Office later than three months after the mailined patent term adjustment. See 37 CFR 1.704(b).		reply be timely filed irty (30) days will be considered timely. NTHS from the mailing date of this communication. BANDONED (35 U.S.C. § 133).				
1) 🔽	Responsive to communication(s) filed on 08	May 2003 .					
2a) <u></u> □	This action is FINAL . 2b)⊠ T	his action is non-final.					
3)	3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.						
Dispositi	ion of Claims	LX parte Quayle, 1955 C	.b. 11, 400 O.G. 210.				
4) 🖸	Claim(s) 1-21 Sare pending in the application	on.					
	4a) Of the above claim(s) <u>7-21</u> stare withdrawn from consideration.						
5) 🗌	Claim(s) is/are allowed.						
6)[-	Claim(s) <u>1-6</u> is/are rejected.						
7)	Claim(s) is/are objected to.						
8)[-]	Claim(s) 1-21 are subject to restriction and/or	election requirement.					
Applicati	on Papers						
/	The specification is objected to by the Examin						
10)[The drawing(s) filed on <u>10 February 2003</u> is/ar						
	Applicant may not request that any objection to the	<u> </u>					
11) The proposed drawing correction filed on is: a) approved b) disapproved by the Examiner.							
If approved, corrected drawings are required in reply to this Office action. 12) The oath or declaration is objected to by the Examiner.							
,		Xammer.					
_	under 35 U.S.C. §§ 119 and 120	na najaritu undar 25 II C.C.	\$ 110(a) (d) or (f)				
,	13) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).						
a)(All b) Some * c) None of:	ats have been received					
	 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 						
	3. Copies of the certified copies of the prior		· · · ——				
* 5	application from the International B See the attached detailed Office action for a lis	ureau (PCT Rule 17.2(a)).					
14) 🗌 A	Acknowledgment is made of a claim for domes	tic priority under 35 U.S.C	. § 119(e) (to a provisional application).				
) \square The translation of the foreign language pracknowledgment is made of a claim for domes						
Attachmen	t(s)						
2) Notic	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449) Paper No(s)	5) Notice o	v Summary (PTO-413) Paper No(s) f Informal Patent Application (PTO-152)				

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Attorney's Docket Number: 214019US2

Filing Date: 9/19/01

Continuing Data: RCE established 5/8/03

Claimed Foreign Priority Date: 9/21/00 (JPX)

Applicant(s): Sakagami

Examiner: Howard Weiss

Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 5/8/03 has been entered.

Drawings

2. The corrected or substitute drawings were received on 2/10/03. These drawings are acceptable.

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claim 1 is rejected under 35 U.S.C. 103(a) as being unpatentable over Ogura et al. (U.S. Patent No. 6,255,166) and Pradeep et al. (U.S. Patent No. 6,228,713).

Ogura et al. show most aspects of the instant invention (e.g. Figure 1) including:

a semiconductor substrate 10

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a first transistor used as a cell transistor including a first gate insulating film 132 and a first gate electrode 142

- a second transistor used as a selection transistor including a second gate insulating film 131 and a second gate electrode 141
- > said first gate insulating film comprising a charge storage layer 132b made of silicon nitride or tantalum oxide with top 132c and bottom 132a layers of silicon oxide and said charge storage layer existing only below the first gate electrode in an element region

Ogura et al. do not show the first and second transistor isolated by a trench, said charge storage layer restricted from an element isolation region and the height of the charge storage layer above the substrate lower than the height of the material filling said trench. Pradeep et al. teach (e.g. Figure 7A) to isolate memory cells with trench isolations 24 in element isolation regions with the charge storage layer 14 with a height lower than the trench isolations and restricted from said element isolation regions to reduce the masking and etching steps and create a self-aligned structure (Column 1 Lines 49 to 53). It would have been obvious to a person of ordinary skill in the art at the time of invention to isolate memory cells with trench isolations in element isolation regions with the charge storage layer with a height lower than the trench isolations and restricted from said element isolation regions as taught by Pradeep et al. in the device of Ogura et al. to reduce the masking and etching steps and create a self-aligned structure.

 Claims 2, 3 and 5 are rejected under 35 U.S.C. 103(a) as being unpatentable over Ogura et al. and Pradeep et al., as applied to Claim 1 above, and further in view of Reisinger.

Ogura et al. and Pradeep et al. show most aspects of the instant invention (Paragraph 4) except for the thickness ranges and that the thickness of the bottom oxide layer is smaller than the top oxide layer. Reisinger teaches (e.g. Figure 1 and

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Column 5 Lines 45 to 56) to form a triple layer gate insulating layer 5 wit the thicknesses within the claimed ranges and with the thickness of the bottom oxide layer 51 is smaller than the top oxide layer 53 to increase storage density and data retention (Column 2 Lines 7 to 12). It would have been obvious to a person of ordinary skill in the art at the time of invention to form a triple layer gate insulating layer wit the thicknesses within the claimed ranges and with the thickness of the bottom oxide layer is smaller than the top oxide layer as taught by Reisinger in the device of Ogura et al. and Pradeep et al. to increase storage density and data retention.

6. Claim 4 is rejected under 35 U.S.C. 103(a) as being unpatentable over Ogura et al., Pradeep et al. and Reisinger, as applied to Claim 1 above, and further in view of Agarwal et al. (U.S. Patent No. 6,201,276)

Ogura et al., Pradeep et al. and Reisinger disclose the claimed invention (Paragraph 5) except that the charge storage layer comprising either a silicon nitride or a tantalum oxide film instead of either a strontium titanate or a barium strontium titanate film. Agarwal et al. teach (Column 4 Lines 33 to 36) that either a strontium titinate or a barium strontium titanate film are equivalent structure known in the art. Therefore, because these charge storage films were art-recognized equivalents at the time the invention was made, one of ordinary skill in the art would have found it obvious to substitute either silicon nitride or tantalum oxide for strontium titinate or barium strontium titanate.

7. Claim 6 is rejected under 35 U.S.C. 103(a) as being unpatentable over Ogura et al. and Pradeep et al., as applied to Claim 1 above, and further in view of Fang (U.S. Patent No. 6,023,085).

Ogura et al. and Pradeep et al. show most aspects of the instant invention (Paragraph 4) except for the first peripheral transistor consisting of a third gate

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insulating film and a third gate electrode and a second peripheral transistor consisting of a fourth gate insulating film and a fourth gate electrode and the thicknesses of the third and fourth gate insulating film being different. Fang teaches (e.g. Figure 9H) to have peripheral transistors 332, 342 with gate electrodes 338 and gate insulting films 337,336 of different thicknesses to improve performance and reliability while simplifying manufacture (Column 2 Lines 51 to 54). It would have been obvious to a person of ordinary skill in the art at the time of invention to have peripheral transistors with gate electrodes and gate insulting films of different thicknesses as taught by Fang in the device of Ogura et al. and Pradeep et al. to improve performance and reliability while simplifying manufacture.

Response to Arguments

8. Applicant's arguments with respect to Claims 1 to 6 have been considered but are moot in view of the new ground(s) of rejection.

Conclusion

- 9. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Holbrook et al. (U.S. Patent No. 6,495,853) show the use of trench isolation.
- 10. Papers related to this application may be submitted directly to Art Unit 2814 by facsimile transmission. Papers should be faxed to Art Unit 2814 via the Art Unit 2814 Fax Center located in Crystal Plaza 4, room 3C23. The faxing of such papers must conform with the notice published in the Official Gazette, 1096 OG 30 (15 November 1989). The Art Unit 2814 Fax Center number is (703) 308-7722 or -7724. The Art Unit 2814 Fax Center is to be used only for papers related to Art Unit 2814 applications. The official TC2800 Before-Final, (703) 872-9318, and After-Final, (703)-872-9319 Fax numbers will provide the fax sender with an auto-reply fax verifying receipt of their fax by the USPTO.

11. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Howard Weiss at **(703) 308-4840** and between the hours of 8:00 AM to 4:00 PM (Eastern Standard Time) Monday through Friday or by e-mail via Howard.Weiss@uspto.gov.

Any inquiry of a general nature or relating to the status of this application should be directed to the Group 2800 Receptionist at **(703) 308-0956**.

12. The following list is the Examiner's field of search for the present Office Action:

Field of Search	Date
U.S. Class / Subclass(es): 257/ 324,326	thru 7/8/03
Other Documentation: none	
Electronic Database(s): EAST	thru 7/8/02

HW/hw 9 July 2003 Howard Weiss Examiner

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